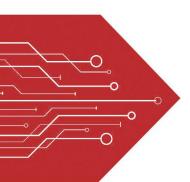
MSKSEMI















ESD

TVS

TSS

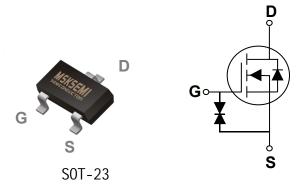
MOV

GDT

PLED

Broduct data sheet





BVDSS	RDSON	ID
55V	1.2R	0.3A

Features

- 55V,0.3A, RDS(ON) =1.2Ω@VGS=10V
- Improved dv/dt capability
- Fast switching
- Green Device Available
- G-S ESD Protection Diode Embedded
- ESD protected up to 2KV

Applications

- Motor Drive
- Power Tools
- LED Lighting

Absolute Maximum Ratings T Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	55	V
Vgs	Gate-Source Voltage	±20	V
1-	Drain Current – Continuous (T₄=25°C)	0.3	Α
lD .	Drain Current – Continuous (T₄=70°C)	0.16	Α
Ірм	Drain Current – Pulsed¹	0.8	Α
D-	Power Dissipation (T _A =25°C)	0.35	W
Po	Power Dissipation – Derate above 25°C	0.003	W/°C
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		357	°C/W





Electrical Characteristics (T_J=25 , unless otherwise noted)

Off Characteristics

Syn	nbol	Parameter Conditions		Min.	Тур.	Max.	Unit
BV	/DSS	Drain-Source Breakdown Voltage V _{GS} =0V , I _D =250uA		55			V
		Drain Source Leakage Current	V _{DS} =55V , V _{GS} =0V , T _J =25°C			1	uA
IC	OSS	Drain-Source Leakage Current	V _{DS} =40V , V _{GS} =0V , T _J =125°C			100	uA
lo	GSS	Gate-Source Leakage Current	Vgs= ±20V , Vps=0V			±10	uA

On Characteristics

Process	Ctatia Dunin Course On Bosistanas	Vgs=10V , ID=0.2A		1.2	1.5	Ω
RDS(ON)	Static Drain-Source On-Resistance	Vgs=4.5V , Ip=0.1A		1.5	2.5	Ω
V _G S(th)	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	8.0	1.1	1.5	V
gfs	Forward Transconductance	V _{DS} =10V , I _D =0.2A		0.5		S

Dynamic and switching Characteristics

Qg	Total Gate Charge ^{2, 3}		 3.7	I	
Qgs	Gate-Source Charge ^{2,3}	V _{DS} =30V , V _{GS} =10V , I _D =0.2A	 0.9	-	nC
Qgd	Gate-Drain Charge ^{2, 3}		 0.4		
Td(on)	Turn-On Delay Time ^{2,3}		 3		
Tr	Rise Time ^{2, 3} V_{DD} =30V , V_{GS} =10V , R_G =6 Ω		 5		
Td(off)	Turn-Off Delay Time ^{2,3}	ID=0.2A	 14		ns
Tf	Fall Time ^{2,3}		 9		
Ciss	Input Capacitance		 25.5		
Coss	Output Capacitance	V _{DS} =30V , V _{GS} =0V , F=1MHz	 17		pF
Crss	Reverse Transfer Capacitance		 7.8		

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter Conditions		Min.	Тур.	Max.	Unit
ls	Continuous Source Current	\/\/\/\/			0.3	Α
lsм	Pulsed Source Current	V _G =V _D =0V , Force Current			0.6	Α
VsD	Diode Forward Voltage	V _G s=0V , I _S =0.2A , T _J =25°C			1.4	V
trr	Reverse Recovery Time	V _R =50V, I _S =0.2A		3.4		ns
Qrr	Reverse Recovery Charge	dl/dt=100A/µs, Tյ=25°C		0.7		nC

- Note:
 1. Repetitive Rating: Pulsed width limited by maximum junction temperature.
- The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%.
 Essentially independent of operating temperature.

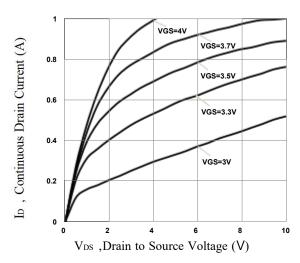


Fig. 1 Typical Output Characteristics

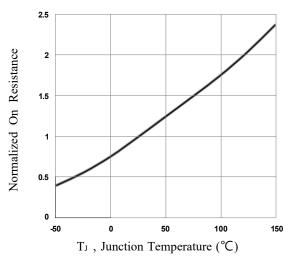


Fig. 3 Normalized RDSON vs. $T_{\rm J}$

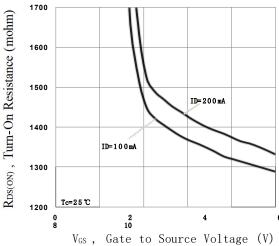


Fig. 5 Turn-On Resistance vs. V_{GS}

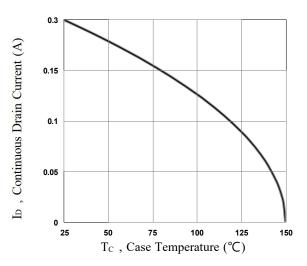


Fig. 2 Continuous Drain Current vs. Tc

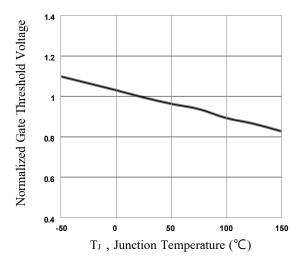


Fig. 4 Normalized V_{th} vs. T_J

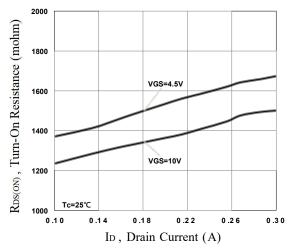


Fig. 6 Turn-On Resistance vs. ID



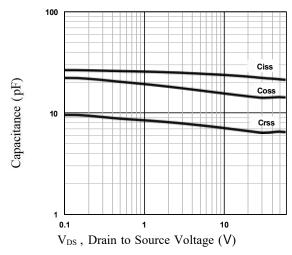
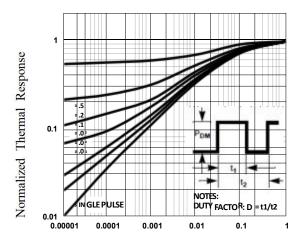


Fig. **7** Capacitance Characteristics



Square Wave Pulse Duration (s)

Fig. 9 Normalized Transient

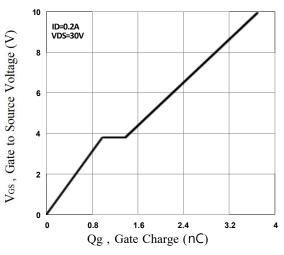
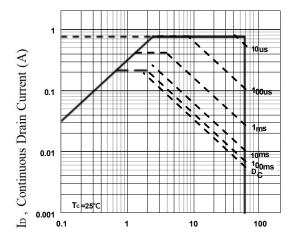


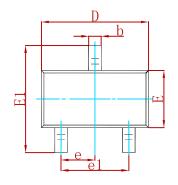
Fig. 8 Gate Charge Characteristics

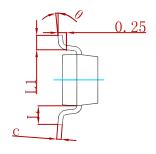


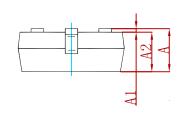
V_{DS}, Drain to Source Voltage (V)

Fig. 10 Maximum Safe Operation Area

PACKAGE MECHANICAL DATA

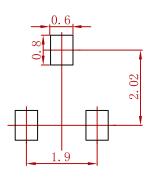






Cumbal	Dimensions	In Millimeters	Dimension	s In Inches
Symbol	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950) TYP	0.037	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550	0.550 REF 0.022 REF		2 REF
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

Suggested Pad Layout



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
LBSS138LT1G-MS	SOT-23	3000



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